OA-11

OA-11 is used as a substrate for liquid crystal displays and OLED displays, as well as a substrate for the formation of various thin films. OA-11 has particularly low deformation and deflection of gravity properties.

The substrate is both very thin and highly useful. The high dimensional stability of this glass substrate allows it to withstand high-temperature processes, which makes it suitable for use in high-quality displays.



1. Smooth surface

Glass substrates formed using overflow technology exhibit flat precision surfaces.

2. Alkali-free

With a maximum alkali oxide content of 0.1%, this product does not degrade the conductive properties of thin-film transistors.

3. Thermal dimensional stability

A high strain point and a low thermal expansion coefficient give OA-11 high thermal dimensional stability during the TFT forming process and other heat treatment processes.

4. Chemically stable surface

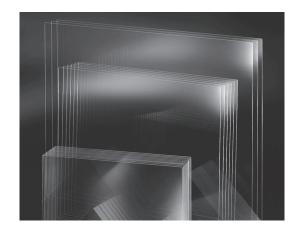
OA-11 is inert to treating agents used in the semiconductor process and the TFT forming process, so surfaces retain pristine quality.

5. Available in multiple size options

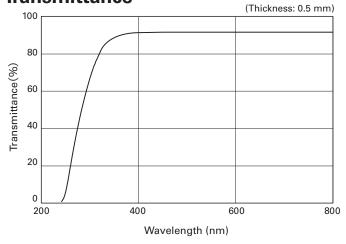
A wide range of sizes, from G1 to ultra-large G10.5, are available.

Properties

Properties/Glass Code			OA-11
Density		$\times 10^3 \text{kg/m}^3$	2.52
Coefficient of thermal expansion	30-380°C	× 10-7/K	37
Strain point		°C	685
Young's modulus		GPa	78
Poisson's ratio			0.2
Vickers hardness	Hv		620
Volume resistivity Log p	350°C	Ω·cm	13.0
Dielectric constant	1MHz, RT		5.6
tan δ	1MHz, RT		0.001
Light transmittance	λ =550nm	%	92
Refractive index (n _d)	587.6nm		1.53
	10% HCI (80°C-60min)		No visual change
Chemical durability	63 BHF (20°C-3min)		No visual change
Alkali oxide content		wt%	0.1 max.
As, Sb content		wt%	Less than 0.1



Transmittance



Dimensions

(mm) Length Center Tolerance Center Tolerance 370 ± 0.2 470 ± 0.3 ± 0.35 $\pm~0.4$ 550 650 730 $\pm~0.5$ 920 $\pm~0.6$ 1100 ± 0.7 1300 ± 0.8 1500 ± 1.0 1850 \pm 1.2 1950 ± 1.4 2250 ± 1.6

2500

3370

(mm) Thickness Center Tolerance 0.50 ± 0.05 0.40 ± 0.04 0.30 ± 0.03

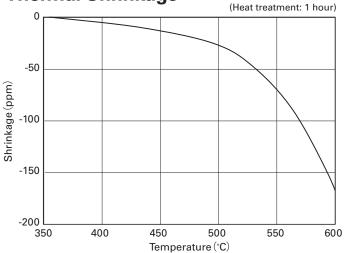
± 2.0 Consult us for other dimensions.

± 1.6

2200

2940

Thermal Shrinkage



Flatness

Subjects	Specifications	Remarks
Waviness	0.06μ m max.	Standard length 20mm (SEMI D15-1296)
Surface Roughness	Ra: 0.2nm	AFM

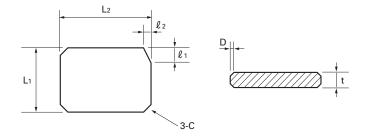
Only on the pattern surface

Corner Cut Orientation Corner 1-C Chamfering 3-C l1.l2 D Simple Round Shape Center Tolerance Center Tolerance 0.05-0.55 4.0 \pm 1.0 1.5 ± 1.0

± 1.7

± 2.2

Consult us for other shapes.



Surface Defects (Scratch, Dirt)

None observed in surface inspection carried out using oblique illuminations as shown in the following table.

Grade A	Grade B
10000 lx	1500 lx

Only on the pattern surface

Processing Defects (Peripheral Chipping and Cracking)

Size of Defects (mm)	Maximum Number Allowed
> 1.0	None
≦ 1.0	Disregard

There were no sign of chips nor cracks developing in the glass. Inspection conditions: Surface inspection at 1500 lux.